

09891310\_CLS

Most Frequently Occurring Classifications of Patents Returned  
From A Search of 09891310 on February 10, 2004

Original Classifications

23 714/727  
5 714/726  
2 324/765  
2 714/724  
2 714/733  
2 716/4

Cross-Reference Classifications

7 714/30  
7 714/726  
5 714/727  
5 714/729  
5 714/733  
4 714/731  
3 326/86  
3 714/724  
3 714/728  
2 324/73.1  
2 324/765  
2 365/201  
2 714/732  
2 714/734  
2 714/738  
2 716/18

Combined Classifications

28 714/727  
12 714/726  
8 714/30  
7 714/733  
5 714/724  
5 714/729  
4 324/765  
4 714/728  
4 714/731  
3 326/86  
3 714/734  
3 714/738  
2 324/158.1  
2 324/73.1  
2 365/201  
2 714/732  
2 714/736

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2 716/18  
2 716/4

09891310\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09891310 on February 10, 2004

28	714/727	(23 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
	714/727	...Boundary scan
12	714/726	(5 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive scan design (LSSD))
8	714/30	(1 OR, 7 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/100	DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
	714/1	.Reliability and availability
	714/25	..Fault locating (i.e., diagnosis or testing)
	714/27	...Particular access structure
	714/30	....Built-in hardware for diagnosing or testing within-system component (e.g., microprocessor or test mode circuit, scan path)
7	714/733	(2 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/733	..Built-in testing circuit (BILBO)
5	714/724	(2 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT

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DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing

5 714/729 (0 OR, 5 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))  
714/729 ...Plural scan paths

4 324/765 (2 OR, 2 XR)  
Class 324 : ELECTRICITY: MEASURING AND TESTING  
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF  
ELECTRIC COMPONENTS  
324/537 .Of individual circuit component or element  
324/765 ..Test of semiconductor device

4 714/728 (1 OR, 3 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))  
714/728 ...Random pattern generation (includes  
pseudorandom pattern)

4 714/731 (0 OR, 4 XR)  
Class 714 : ERROR DETECTION/CORRECTION AND FAULT  
DETECTION/RECOVERY  
714/699 PULSE OR DATA ERROR HANDLING  
714/724 .Digital logic testing  
714/726 ..Scan path testing (e.g., level sensitive sca  
n  
design (LSSD))  
714/731 ...Clock or synchronization

3 326/86 (0 OR, 3 XR)  
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY  
326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT,  
ETC.)  
326/82 .Current driving (e.g., fan in/out, off chip  
driving, etc.)

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326/83	..Field-effect transistor
326/86	...Bus driving
3	714/734 (1 OR, 2 XR)
Class	714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/734	..Structural (in-circuit test)
3	714/738 (1 OR, 2 XR)
Class	714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/738	..Including test pattern generator
2	324/158.1 (1 OR, 1 XR)
Class	324 : ELECTRICITY: MEASURING AND TESTING
324/158.1	MISCELLANEOUS
2	324/73.1 (0 OR, 2 XR)
Class	324 : ELECTRICITY: MEASURING AND TESTING
324/73.1	PLURAL, AUTOMATICALLY SEQUENTIAL TESTS
2	365/201 (0 OR, 2 XR)
Class	365 : STATIC INFORMATION STORAGE AND RETRIEVAL
365/189.01	READ/WRITE CIRCUIT
365/201	.Testing
2	714/732 (0 OR, 2 XR)
Class	714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/732	..Signature analysis
2	714/736 (1 OR, 1 XR)
Class	714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/699	PULSE OR DATA ERROR HANDLING
714/724	.Digital logic testing
714/736	..Device response compared to expected fault-free response
2	716/18 (0 OR, 2 XR)
Class	716 : DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK

		09891310_CLSTITLES
	716/1	CIRCUIT DESIGN
	716/18	.Logical circuit synthesizer
2	716/4	(2 OR, 0 XR)
	Class	716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
		CIRCUIT OR SEMICONDUCTOR MASK
	716/1	CIRCUIT DESIGN
	716/4	.Testing or evaluating

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PLUS Search Results for S/N 09891310, Searched February 10, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6556037  
5631912  
6163864  
5872796  
5892778  
6122762  
6219812  
6219812  
5598421  
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6499124  
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5928374  
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5341096  
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5736849  
5042034  
5299136  
5500862  
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6321355  
6324096  
6343365  
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6370665  
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6519728  
5640404  
6000050  
6449755  
6324614  
6408413  
5357572  
5936423  
5968195  
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